

METHOD FOR QUANTIFYING SAFE
OPERATING AREA FOR BIPOLAR
JUNCTION TRANSISTOR
Inventors: Kim et al.
Atty. Docket No. P05779

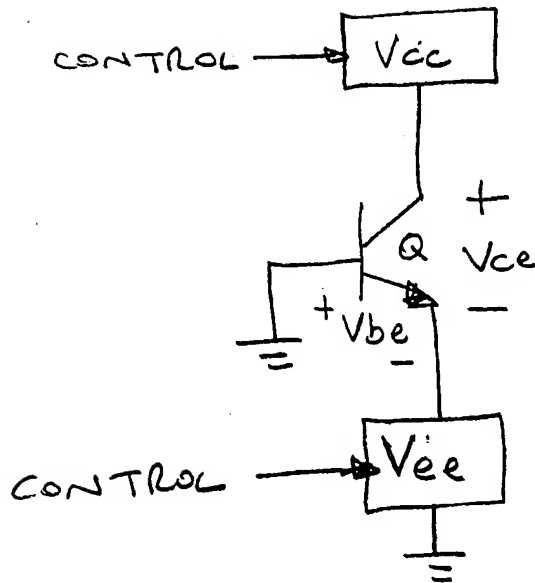


FIGURE 1A
(PRIOR ART)

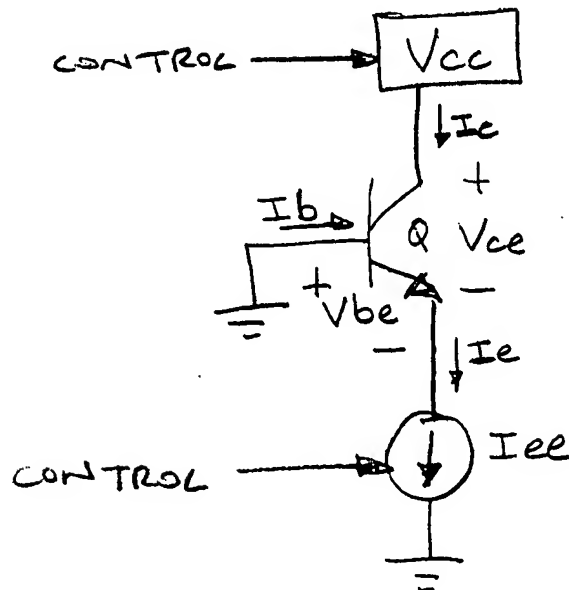


FIGURE 2A
(PRIOR ART)

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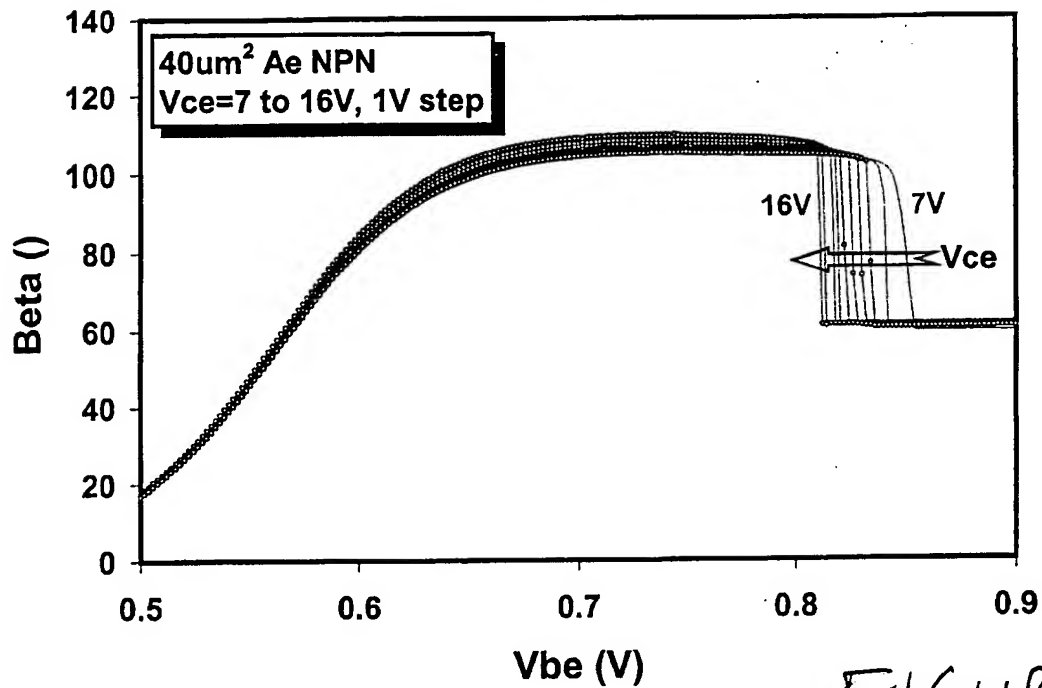


FIGURE 1B
(PRIOR ART)

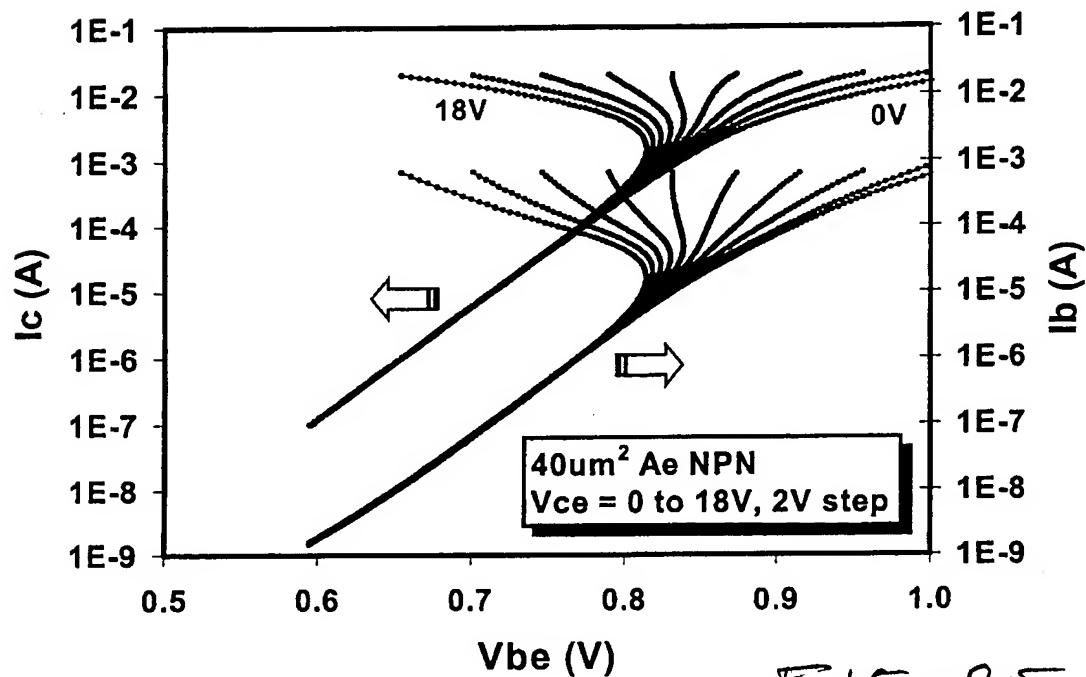


FIGURE 2B
(PRIOR ART)

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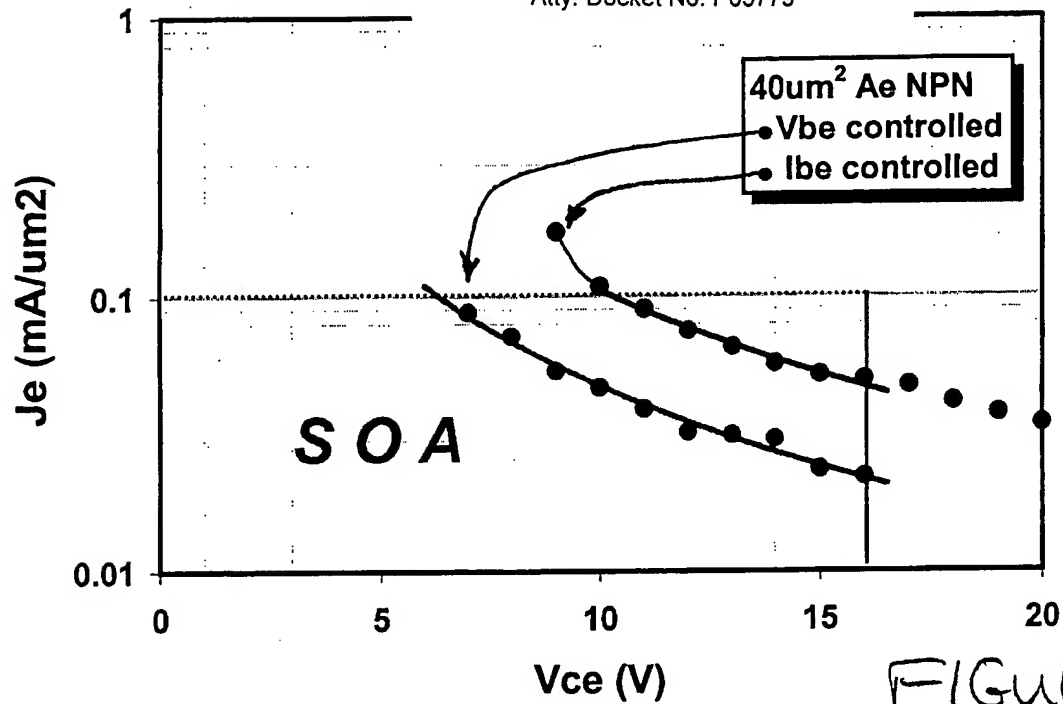


FIGURE 3
(PRIOR ART)

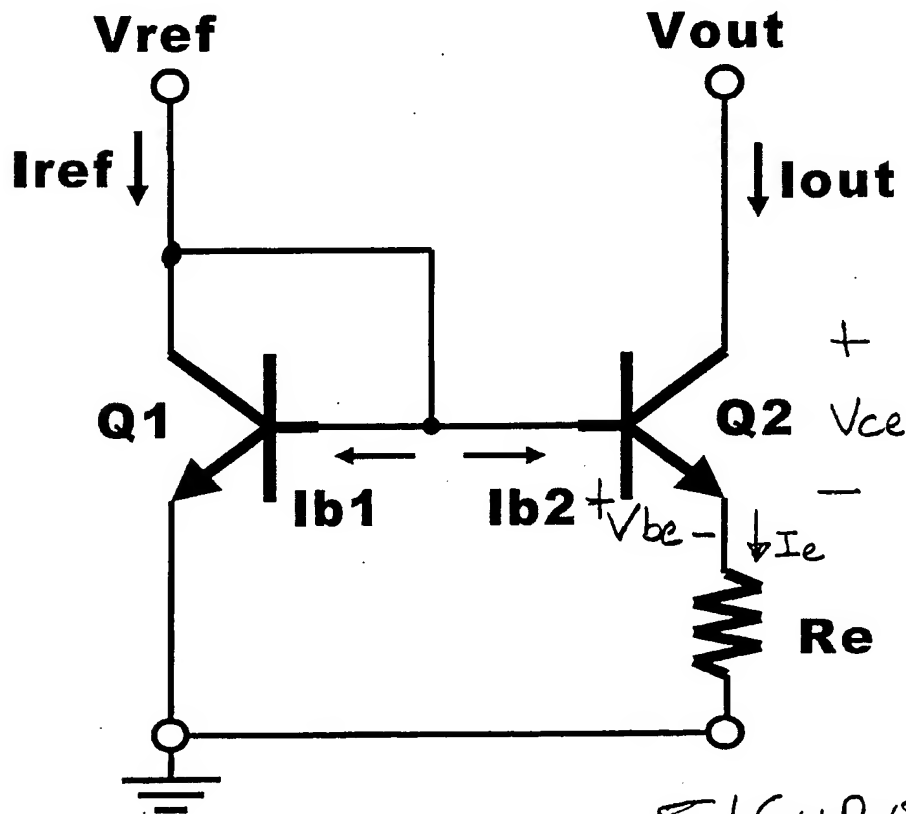
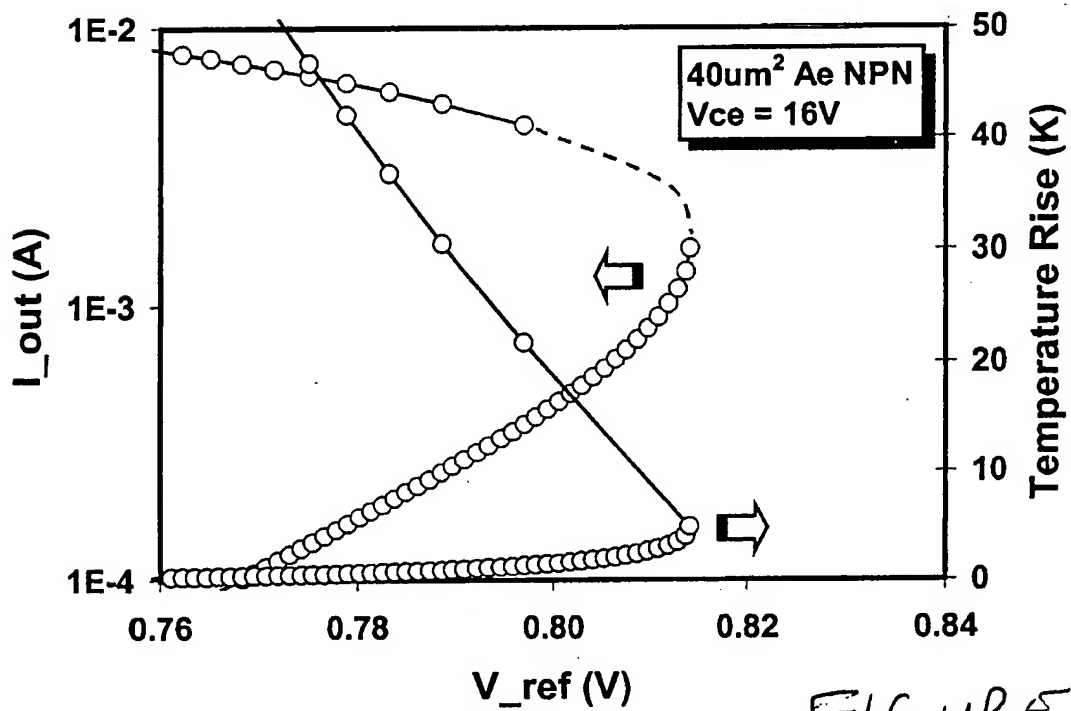
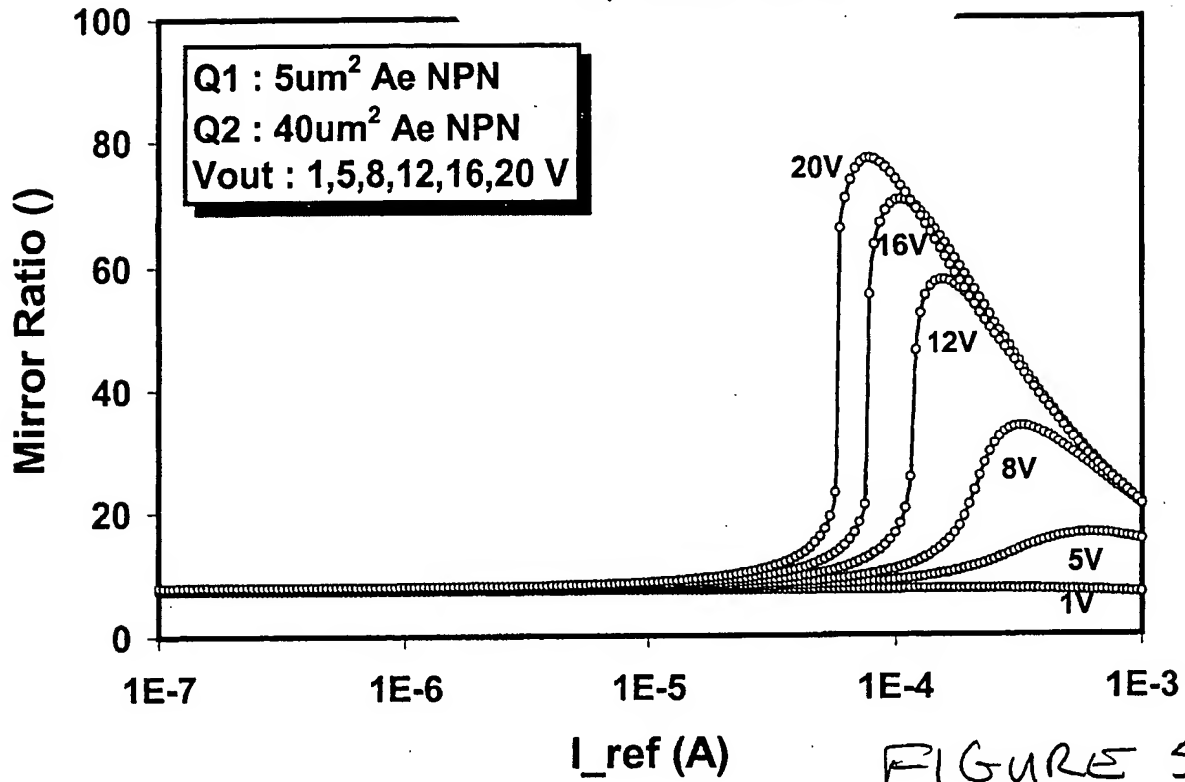


FIGURE 4

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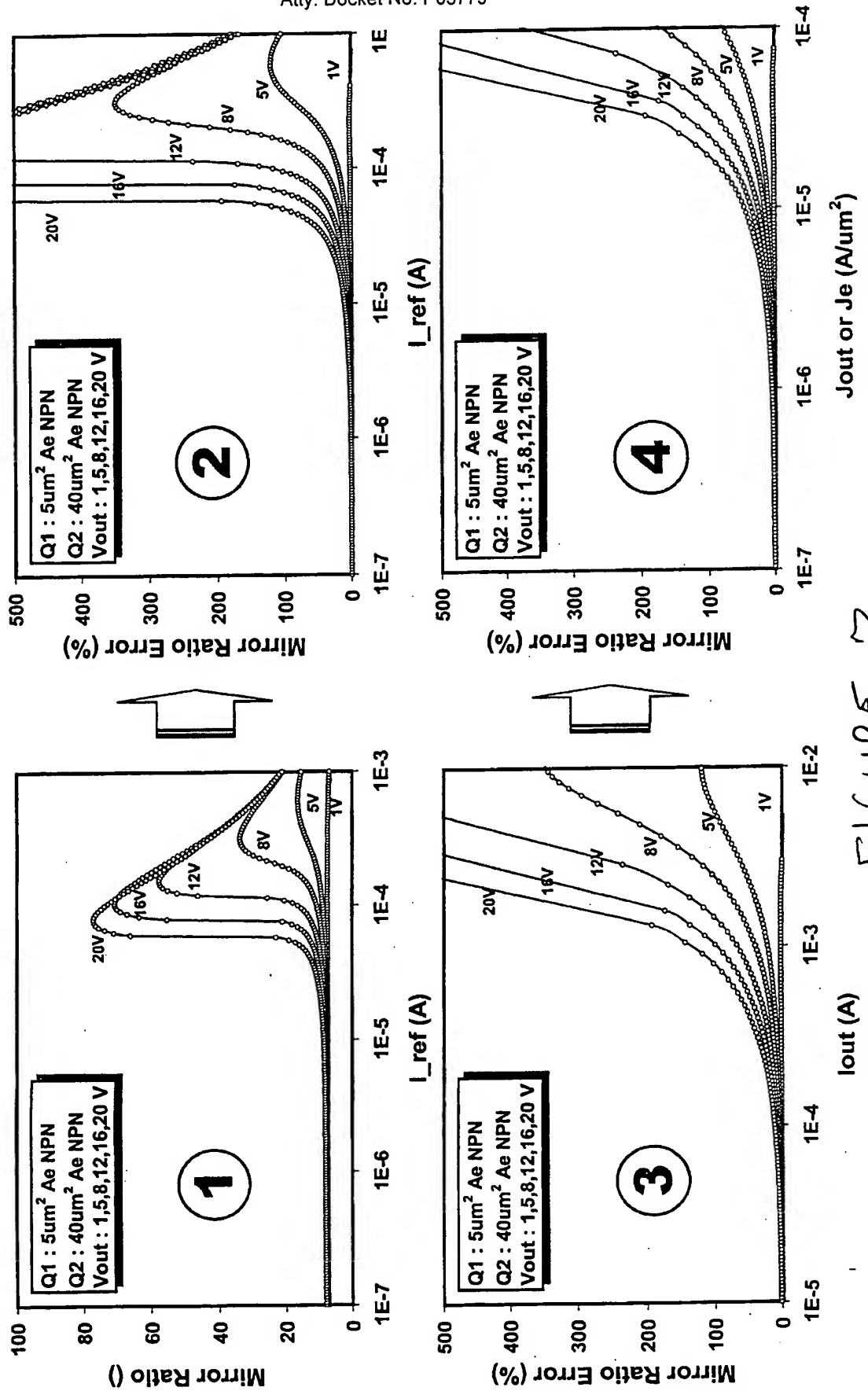


FIGURE 7

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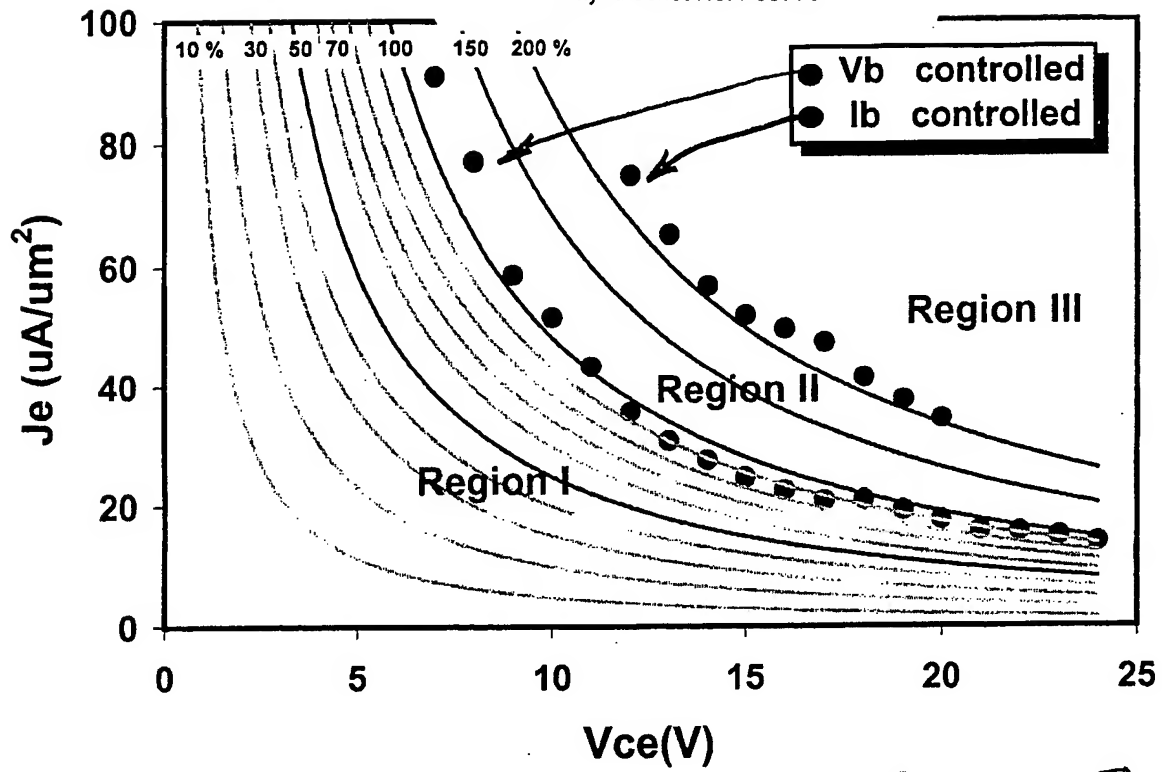


FIGURE 8

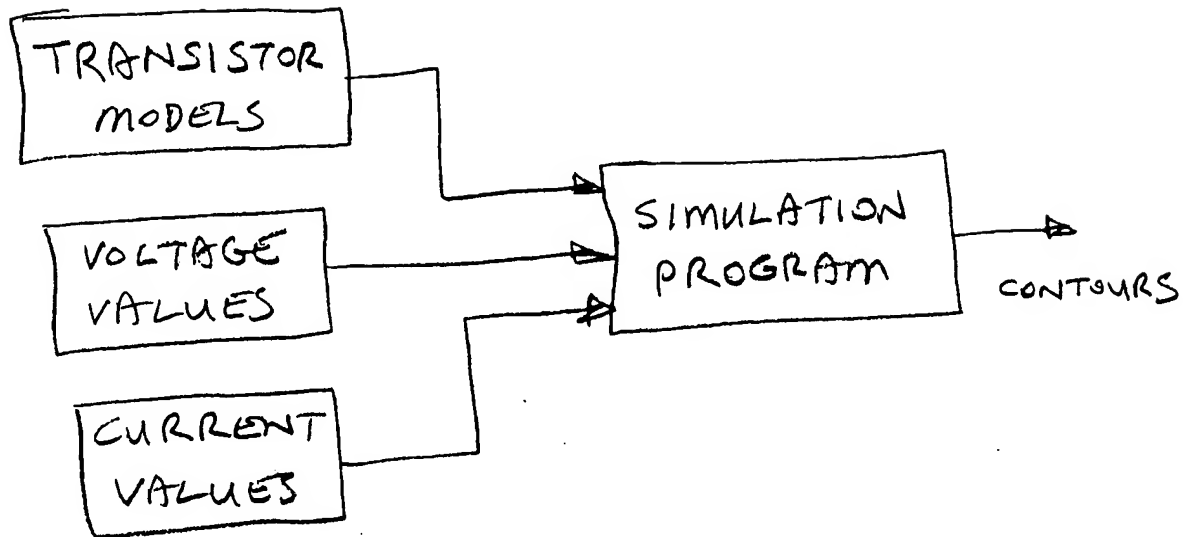


FIGURE 9